



PATENT

IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:
Mak, et al

Serial No.: 10/754,321

Filed: January 9, 2004

For: Integrated Phase Angle
and Optical Critical
Dimension Measurement
Metrology for Feed
Forward and Feedback
Process Control

MAIL STOP
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Group Art Unit: 2877
Examiner: Unknown

CERTIFICATE OF MAILING
37 CFR 1.8

I hereby certify that this correspondence is being deposited on November 9, 2005 with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.

November 9, 2005
Date

Kiru shi
Signature

Dear Sir:

STATUS INQUIRY

More than 22 months have passed since

the filing of this application on January 9, 2004.

the filing of . response on .

No communication has been received from the Patent and Trademark Office indicating action on this application or response.

Kindly advise the undersigned of the present status of this application. A stamped return-addressed envelope is provided.

Respectfully submitted,

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